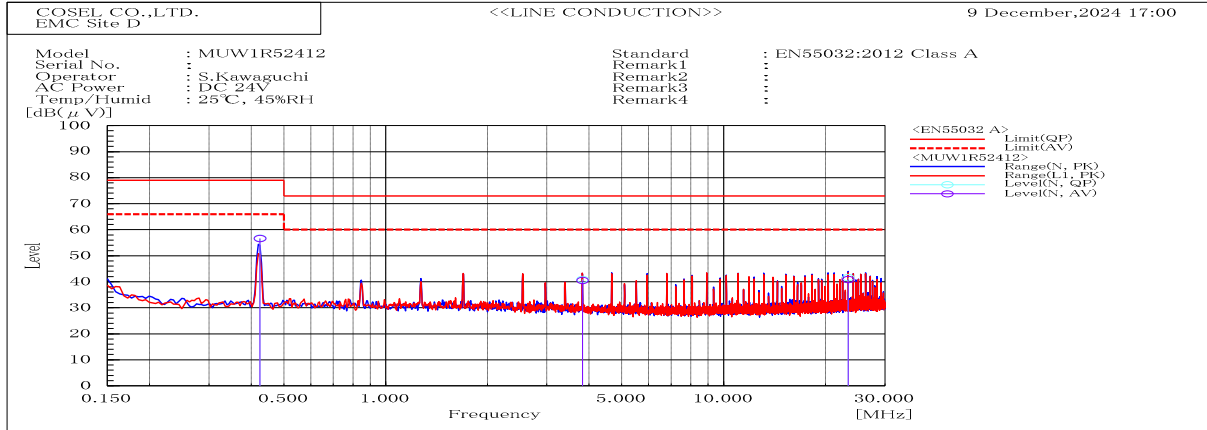
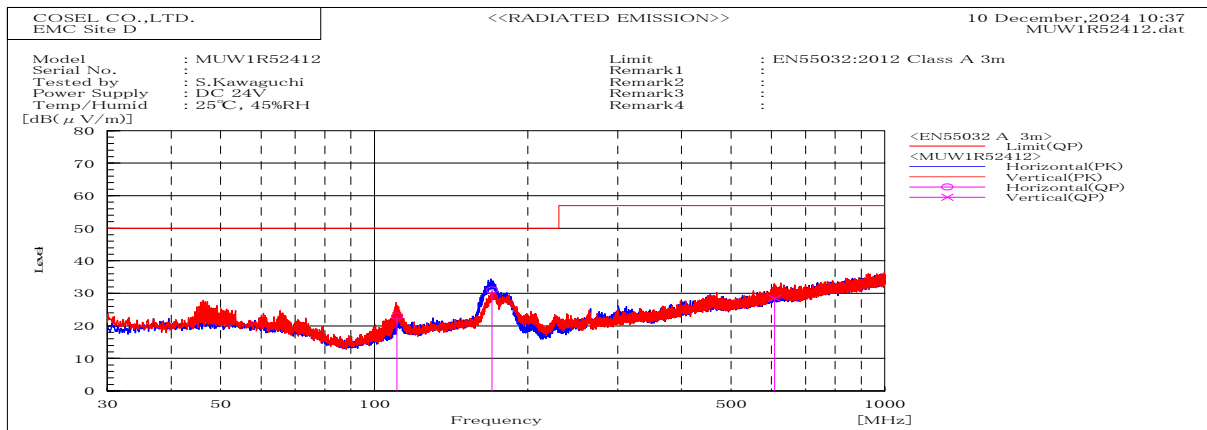


DATA SHEET		Date	05-Mar-25
Model	MUW1R52412	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi



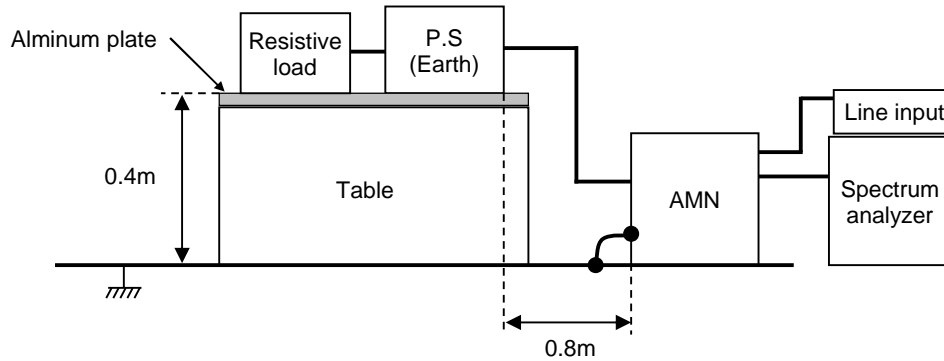
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.425	N	56.8	56.6	79	66	22.2	9.4	Pass	
3.822	N	40.9	40.5	73	60	32.1	19.5	Pass	
23.36	N	41.6	40.9	73	60	31.4	19.1	Pass	



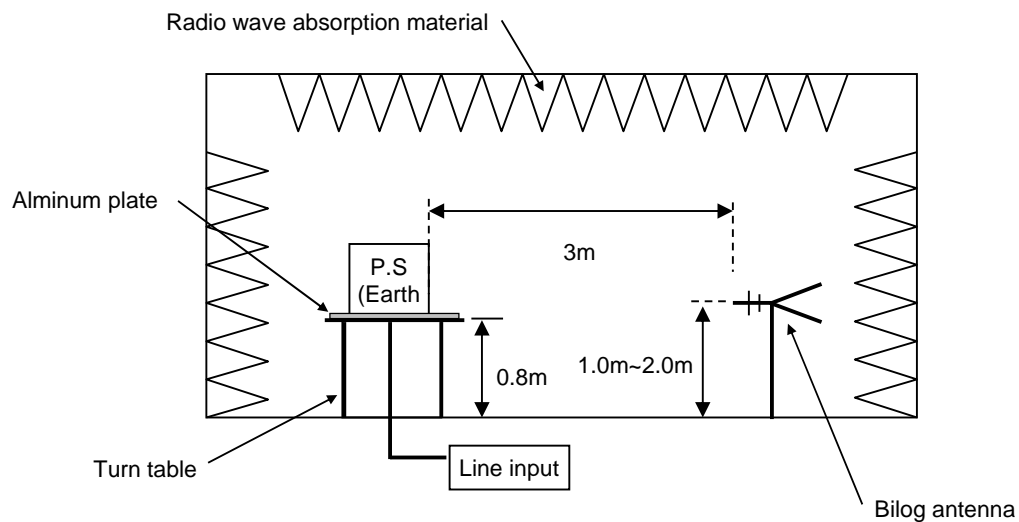
Frequency MHz	Polarization	Stability	Level dB(μV/m)		Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP					
170.222	H	Stable	31.1	50	18.9	Pass	200	39.5	
110.775	H	Stable	23	50	27	Pass	184	236.4	
608.808	V	Stable	28.5	57	28.5	Pass	101.6	101.5	

DATA SHEET		Date	05-Mar-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	45 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission



Conditions

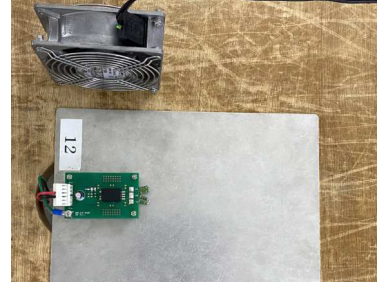
Test : EMI
Model Name: MUW1R5□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

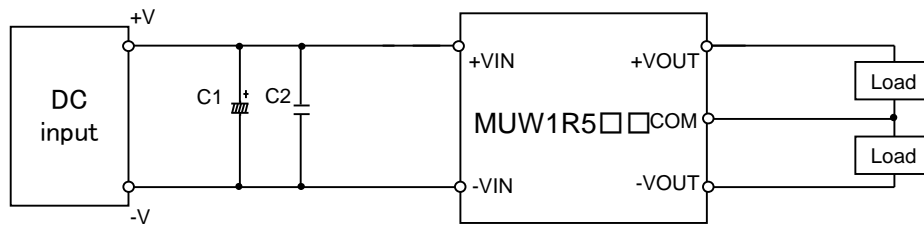


Fig.1 MUW1R505□, MUW1R512□, MUW1R524□ Testing circuitry

- | | | | |
|------|-----------|-----------------|---|
| C1 : | MUW1R505□ | 16V 220 μ F | Electric capacitor (UPWseries NICHICON) |
| | MUW1R512□ | 50V 100 μ F | Electric capacitor (UPWseries NICHICON) |
| | MUW1R524□ | - | |
| C2 : | MUW1R505□ | 16V 22 μ F | Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING) |
| | MUW1R512□ | 25V 22 μ F | Ceramic capacitor (C3216JB1E226MT TDK) |
| | MUW1R524□ | 50V 10 μ F | Ceramic capacitor (C3216X7R1H106KT TDK) |

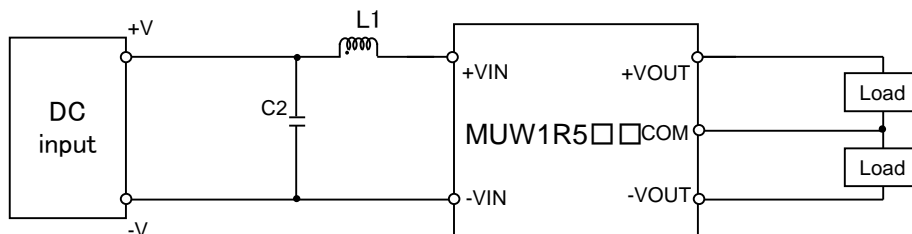


Fig.2 MUW1R548□ Testing circuitry

- | | | | |
|------|-----------|------------------|--|
| C2 : | MUW1R548□ | 100V 2.2 μ F | Ceramic capacitor (C3216X7S2A225KT TDK) |
| L1 : | MUW1R548□ | 520mA 15 μ H | Inductor (LQH32PN150MN0L MURATA MANUFACTURING) |